

L Number	Hits	Search Text	DB	Time stamp
-	155637	polysi or polysilicon or (poly or polycrystal\$5) adj (si or silicon)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 13:43
-	656558	stress\$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 09:04
-	3947590	anneal\$4 or heat\$4 or thermal\$3 adj3 treat\$5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 13:48
-	878976	gate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 13:45
-	718828	oxidi\$5 or oxidat\$5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 11:33
-	30152	((oxidi\$5 or oxidat\$5) same (polysi or polysilicon or (poly or polycrystal\$5) adj (si or silicon))) and (stress\$4 same (anneal\$4 or heat\$4 or thermal\$3 adj3 treat\$5)) and gate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 09:10
-	114339	stress\$4 same (anneal\$4 or heat\$4 or thermal\$3 adj3 treat\$5)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 09:10
-	956	((oxidi\$5 or oxidat\$5) same (polysi or polysilicon or (poly or polycrystal\$5) adj (si or silicon))) and (stress\$4 same (anneal\$4 or heat\$4 or thermal\$3 adj3 treat\$5)) and gate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 09:12
-	2478932	tungsten or w	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 13:57
-	643	((((oxidi\$5 or oxidat\$5) same (polysi or polysilicon or (poly or polycrystal\$5) adj (si or silicon))) and (stress\$4 same (anneal\$4 or heat\$4 or thermal\$3 adj3 treat\$5)) and gate) and (tungsten or w)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 09:24
-	19778	gate with stack\$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 09:26
-	182	((oxidi\$5 or oxidat\$5) same (polysi or polysilicon or (poly or polycrystal\$5) adj (si or silicon))) and (stress\$4 same (anneal\$4 or heat\$4 or thermal\$3 adj3 treat\$5)) and (gate with stack\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 11:32
-	2513	438/585.ccls. or 438/592.ccls. or 438/595.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 10:06
-	546619	defect or trap	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 11:32

-	6508889	suppress\$4 or reduc\$4 or decreas\$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 11:34
-	720568	oxidi\$5 or oxidat\$5 or reoxidi\$5 or reoxidat\$5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 13:43
-	7352191	suppress\$4 or reduc\$4 or decreas\$4 or releas\$5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 11:34
-	50316	(anneal\$4 or heat\$4 or thermal\$3 adj3 treat\$5) same (suppress\$4 or reduc\$4 or decreas\$4 or releas\$5) same (oxidi\$5 or oxidat\$5 or reoxidi\$5 or reoxidat\$5)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 11:37
-	30328	(oxidi\$5 or oxidat\$5 or reoxidi\$5 or reoxidat\$5) same (polysi or polysilicon or (poly or polycrystal\$5) adj (si or silicon))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 11:37
-	1857	((anneal\$4 or heat\$4 or thermal\$3 adj3 treat\$5) same (suppress\$4 or reduc\$4 or decreas\$4 or releas\$5) same (oxidi\$5 or oxidat\$5 or reoxidi\$5 or reoxidat\$5)) and ((oxidi\$5 or oxidat\$5 or reoxidi\$5 or reoxidat\$5) same (polysi or polysilicon or (poly or polycrystal\$5) adj (si or silicon))) and gate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 11:37
-	720568	oxidi\$5 or oxidat\$5 or reoxidi\$5 or reoxidat\$5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 14:51
-	155637	polysi or polysilicon or (poly or polycrystal\$5) adj (si or silicon)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 13:45
-	878976	gate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 13:46
-	1523136	oxide or dioxide or "sio.sub.2" or "sio.sub2."	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 13:47
-	2738813	sidewall or side adj2 wall or edge	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 13:48
-	3947590	anneal\$4 or heat\$4 or thermal\$3 adj3 treat\$5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 13:49
-	30115	(oxidi\$5 or oxidat\$5 or reoxidi\$5 or reoxidat\$5 ) near10 ((polysi or polysilicon or (poly or polycrystal\$5) adj (si or silicon) ) or gate )	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 13:51

-	35576	(oxide or dioxide or "sio.sub.2" or "sio.sub2.") near10 (sidewall or side adj2 wall or edge)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 13:53
-	9036	((oxidi\$5 or oxidat\$5 or reoxidi\$5 or reoxidat\$5 ) near10 ((polysi or polysilicon or (poly or polycrystal\$5) adj (si or silicon) ) or gate )) and ((oxide or dioxide or "sio.sub.2" or "sio.sub2.") near10 (sidewall or side adj2 wall or edge))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 13:54
-	3276	((oxidi\$5 or oxidat\$5 or reoxidi\$5 or reoxidat\$5 ) near10 ((polysi or polysilicon or (poly or polycrystal\$5) adj (si or silicon) ) or gate )) same ((oxide or dioxide or "sio.sub.2" or "sio.sub2.") near10 (sidewall or side adj2 wall or edge))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 13:56
-	512	((((oxidi\$5 or oxidat\$5 or reoxidi\$5 or reoxidat\$5 ) near10 ((polysi or polysilicon or (poly or polycrystal\$5) adj (si or silicon) ) or gate )) same ((oxide or dioxide or "sio.sub.2" or "sio.sub2.") near10 (sidewall or side adj2 wall or edge))) same (anneal\$4 or heat\$4 or thermal\$3 adj3 treat\$5 )	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 13:56
-	2478932	tungsten or w	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 13:57
-	11519	(polysi or polysilicon or (poly or polycrystal\$5) adj (si or silicon) ) same gate same (tungsten or w )	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 13:58
-	141	(((((oxidi\$5 or oxidat\$5 or reoxidi\$5 or reoxidat\$5 ) near10 ((polysi or polysilicon or (poly or polycrystal\$5) adj (si or silicon) ) or gate )) same ((oxide or dioxide or "sio.sub.2" or "sio.sub2.") near10 (sidewall or side adj2 wall or edge))) same (anneal\$4 or heat\$4 or thermal\$3 adj3 treat\$5 )) and ((polysi or polysilicon or (poly or polycrystal\$5) adj (si or silicon) ) same gate same (tungsten or w ))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 14:50
-	141	(((((oxidi\$5 or oxidat\$5 or reoxidi\$5 or reoxidat\$5 ) near10 ((polysi or polysilicon or (poly or polycrystal\$5) adj (si or silicon) ) or gate )) same ((oxide or dioxide or "sio.sub.2" or "sio.sub2.") near10 (sidewall or side adj2 wall or edge))) same (anneal\$4 or heat\$4 or thermal\$3 adj3 treat\$5 )) and ((polysi or polysilicon or (poly or polycrystal\$5) adj (si or silicon) ) same gate same (tungsten or w ))) and (anneal\$4 or heat\$4 or thermal\$3 adj3 treat\$5 )	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 14:21
-	8935	selectivi\$4 near3 (oxidi\$5 or oxidat\$5) or reoxidi\$5 or reoxidat\$5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 14:53
-	635	(selectivi\$4 near3 (oxidi\$5 or oxidat\$5) or reoxidi\$5 or reoxidat\$5 ) near15 ((polysi or polysilicon or (poly or polycrystal\$5) adj (si or silicon) ) or gate )	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 14:55

-	19977	(oxide or dioxide or "sio.sub.2" or "sio.sub2.") near20 ((sidewall or side adj2 wall or edge) or side adj2 surface) near20 ((polysi or polysilicon or (poly or polycrystal\$5) adj (si or silicon) ) or gate )	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 14:59
-	116	((selectivi\$4 near3 (oxidi\$5 or oxidat\$5) or reoxidi\$5 or reoxidat\$5 ) near15 ((polysi or polysilicon or (poly or polycrystal\$5) adj (si or silicon) ) or gate )) same ((oxide or dioxide or "sio.sub.2" or "sio.sub2.") near20 ((sidewall or side adj2 wall or edge) or side adj2 surface) near20 ((polysi or polysilicon or (poly or polycrystal\$5) adj (si or silicon) ) or gate ))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 14:59
-	78	((selectivi\$4 near3 (oxidi\$5 or oxidat\$5) or reoxidi\$5 or reoxidat\$5 ) near15 ((polysi or polysilicon or (poly or polycrystal\$5) adj (si or silicon) ) or gate )) same ((oxide or dioxide or "sio.sub.2" or "sio.sub2.") near20 ((sidewall or side adj2 wall or edge) or side adj2 surface) near20 ((polysi or polysilicon or (poly or polycrystal\$5) adj (si or silicon) ) or gate ))) and (anneal\$4 or heat\$4 or thermal\$3 adj3 treat\$5 )	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 15:48
-	1105	438/592.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 15:49